

DYNAMIC CONNECTOR D1000 SERIES

1. Introduction

1.1 Purpose

This document provides the qualification summary of TE Connectivity Dynamic D1200D connectors.

1.2 Scope

This specification covers the electrical, mechanical, and environmental performance of Dynamic D1200 connectors. Testing was performed from 2023/09/13~2023/09/27

1.3 Conclusion

Based on the test results, the parts in the sample list meet the performance requirements of Product Specification, 108-137366, Rev B.

1.4 Product Description

Testing part	Testing part description	Mating housing	Mating contact
2-2349949-6	DYNAMIC D1200D 2.5mm PITCH REC 12POS	2-2468187-6	1827570-2

Table 1 test product



2. Qualification Test Sequence

3.6 Product Qualification Test Sequence

Test Group	Test Group									
	1	2	3	4	5	6	7	8	9	10
Test Item	Test sequence									
Test Examination										
Confirmation of product	1	1	1	1,3	1,3	1,3	1	1	1	1
Termination Resistance							2,5	2,6	2,4	2,6
Dielectric withstanding voltage										4,8
Insulation Resistance										3,7
Temperature rising					2					
Vibration (High Frequency)							3			
Physical Shock							4			
Connector Mating Force								3		
Connector Unmating Force								4		
Contact Insertion Force				2						
Contact Mating Force per PIN		2								
Contact Unmating Force per PIN		3								
Crimping tensile strength	2									
Durability								5		
Housing Locking Strength			2							
Panel Locking Strength										
Humidity-temperature cycling										5
Thermal Shock									3	
Salt Spray										
Contact Retention Force						2				
Temperature life										
Industrial SO ₂										
Post Retention Force										
Solderability										
Resistance to Solder Heat										



Notes:

- a. Numbers indicate the sequence in which the tests are performed, as table 2 shown.
- b. Test group as the table 3 shown.

Testing part	Testing part description	Test group	Plating
2-2349949-6	DYNAMIC D1200D 2.5mm PITCH REC 12POS	3,4,6,7	N/A
2-2468187-6	DYNAMIC D1200D 2.5mm PITCH TAB 12POS	3,4,6,7	N/A

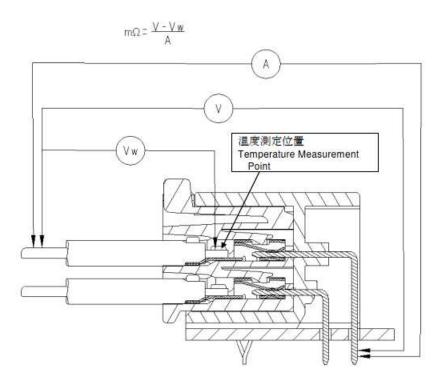
Table 3 test group

3. Test result



Group	Sequence	Test items	Requirements	Test data	Result
Group 3	1	Examination of Product	Meet requirements of product drawing and TE application specification 114-5377	No physical damage	Accept
	2	Housing lock strength	24.5N Min	98. 7~110. 7N	Accept
	3	Examination of Product	Meet requirements of product drawing and TE application specification 114-5377	No physical damage	Accept
Group	Sequence	Test items	Requirements	Test data	Result
	1	Examination of Product	Meet requirements of product drawing and TE application specification 114-5377	No physical damage	Accept
Group 4	2	Contact insertion force	7.84N Max. per contact	2-2468187-6: 4.9 ⁵ 5.8N 2-2349949-6: 2.4 ³ .2N	Accept
	3	Meet requirements of product drawing and TE application specification 114-5377		No physical damage	Accept
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Group	Sequence	Test items	Requirements	Test data	Result
Group 6	1	Examination of Product	Meet requirements of product drawing and TE application specification 114-5377	No physical damage	Accept
	2	Contact retention force	40N Min	Accept	
	3	Examination of Product	Meet requirements of product drawing and TE application specification 114-5377	No physical damage	Accept
Group	Saguanca	Test items	Requirements	Test data	Result
Group	1	Examination of Product	Meet requirements of product drawing and TE application specification 114-5377	No physical damage	Accept
	2	Termination Resistance (Low Level)	10 mΩ Max. (Initial) 20 mΩ Max. (Final)	0.67~1.22 mΩ(intial)	Accept
Group 7	3	Vibration (High Frequency)	20 mΩ Max. (Final)	Refer to sequence 5	Accept
	4	Physical Shock	No electrical discontinuity greater than 1μ Sec. shall occur. 20 mΩ Max. (Final	No physical damage	Accept
	5	Termination Resistance (Low Level)	No electrical discontinuity greater than 1μ Sec. shall occur. 20 mΩ Max. (Final)	0.62 ² .0 mΩ(Final)	Accept
	6	Examination of Product	Meet requirements of product drawing and TE application specification 114-5377	No physical damage	Accept
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- * 測定値から電線抵抗値を引くこと。
 * Take the resistance of wire only away

Fig. 6 総合抵抗 (ローレベル), 温度上昇 Fig. 6 Termination Resistance (Low Level) and Temperature Rising vs. Current Measuring Methods